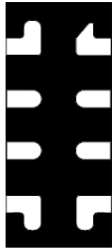
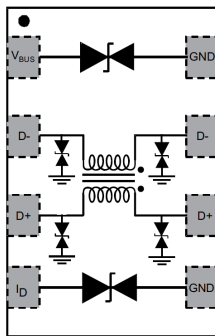


Common mode filter with ESD protection for USB 2.0 interface



Micro QFN-8 L
(pin view)



Features

- Integrated common mode filter
- Differential pair ESD protection
- 16 V V_{BUS} ESD and EOS protection
- ID pin ESD protection
- Low profile micro QFN-8L package
- High bandwidth: > 6 GHz
- Optimized for high speed USB 2.0
- High common mode attenuation at 900 MHz and 1.8 GHz
- Support for audio over USB 2.0 thanks to bidirectional ESD protection
- Ultra compact, low board space
- Low height: < 0.55 mm

Complies with the following standards:

- IEC 61000-4-2 level 4:
 - ± 15 kV (air discharge)
 - ± 8 kV (contact discharge)
- RoHS2 compliant

Applications

Where transient overvoltage protection in ESD sensitive equipment is required, such as:

- Computers
- Printers
- Communication systems
- Cellular phone handsets and accessories
- Video equipment

Description

The ECMF02-4CMX8 affords key component integration such as common mode filter D+ and D- lines and ESD protection on all lines. This device offers an optimized flow-through footprint for USB 2.0 applications.

Product status link

[ECMF02-4CMX8](#)

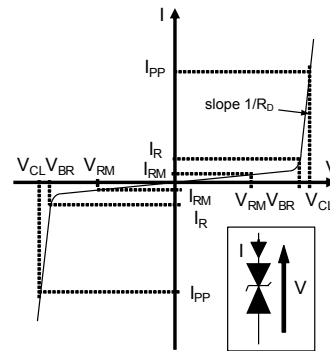
1 Characteristics

Table 1. Absolute maximum ratings ($T_{amb} = 25\text{ °C}$)

| Symbol | Parameter | Value | Unit |
|-----------|--|--|------|
| V_{PP} | Peak pulse voltage | IEC 61000-4-2 (level 4): | kV |
| | | Contact discharge on D+/D- pins | |
| | | Contact discharge on V_{BUS} and ID pins | |
| | | Air discharge on all pins | |
| P_{PP} | Peak pulse power (8/20 μ s) on V_{BUS} | 150 | W |
| I_{PP} | Peak pulse current (8/20 μ s) on V_{BUS} | 4.8 | A |
| T_{op} | Operating ambient temperature range | -30 to +85 | °C |
| T_j | Maximum junction temperature | -40 to +125 | |
| T_{stg} | Storage temperature range | -55 to +150 | |

Figure 1. Electrical characteristics (definitions)

| Symbol | Parameter |
|----------|------------------------------|
| V_{BR} | = Breakdown voltage |
| V_{CL} | = Clamping voltage |
| I_{RM} | = Leakage current @ V_{RM} |
| V_{RM} | = Stand-off voltage |
| I_{PP} | = Peak pulse current |
| R_D | = Dynamic resistance |
| I_R | = Breakdown current |


Table 2. Electrical characteristics ($T_{amb} = 25\text{ °C}$)

| Symbol | Test conditions | Min. | Typ. | Max. | Unit |
|------------------|---|------|------|------|------|
| Data lines | | | | | |
| V _{BR} | I _R = 1 mA | 6 | | | V |
| I _{RM} | V _{RM} = 5.5 V per line | | | 100 | nA |
| R _{DC} | DC serial resistance on data line | | 3 | 4 | Ω |
| V _{BUS} | | | | | |
| V _{BR} | I _R = 1 mA | 15 | 16.5 | 18 | V |
| I _{RM} | V _{RM} = 12 V | | | 50 | nA |
| V _{CL} | Clamping voltage, I _{PP} = 1 A, t _p = 8/20 μs | | | 20 | V |
| | Clamping voltage, I _{PP} = 2.5 A, t _p = 8/20 μs | | | 24 | |
| I _D | | | | | |
| V _{BR} | I _R = 1 mA | 6 | | | V |
| I _{RM} | V _{RM} = 1.5 V per line | | | 100 | nA |

1.1 Characteristics (curves)

Figure 2. SDD21 differential attenuation measurement ($Z_{0\text{ diff}} = 90\ \Omega$) for data lines D+ and D-

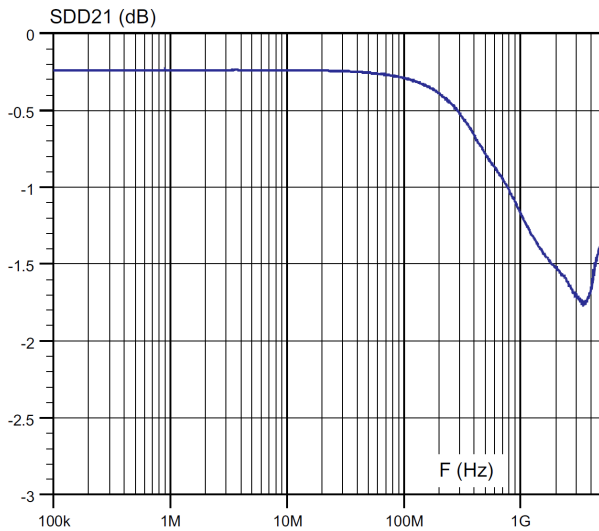


Figure 3. SCC21 common mode attenuation measurement ($Z_{0\text{ com}} = 45\ \Omega$)

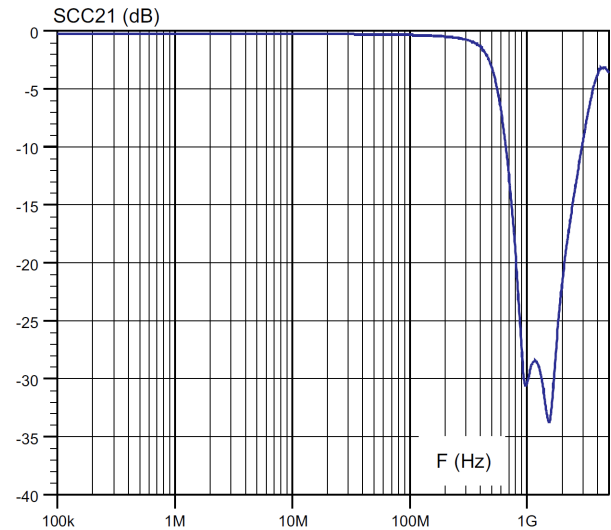


Figure 4. ID frequency response measurement ($Z_0 = 75\ \Omega$)

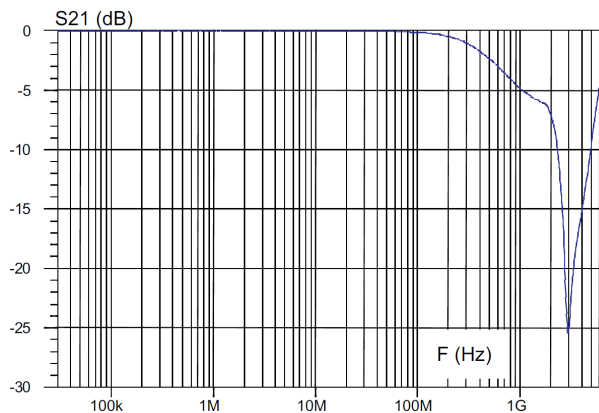


Figure 5. Differential (Z_{DD21}) and common mode (Z_{CC21}) impedance versus frequency

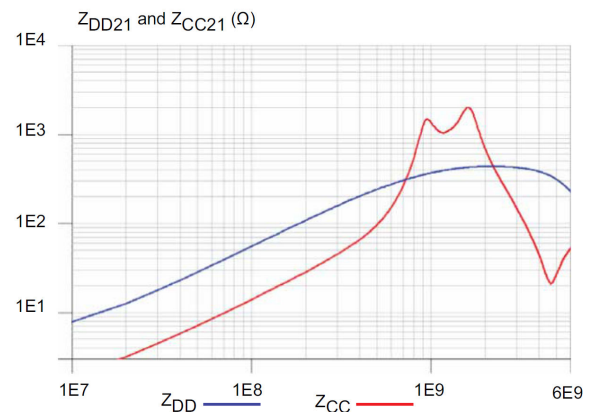


Figure 6. ESD test conditions

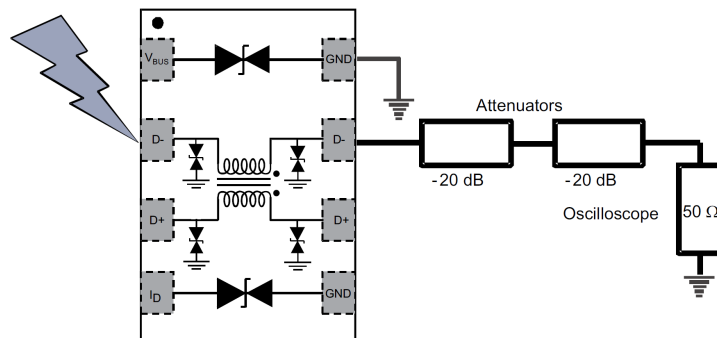


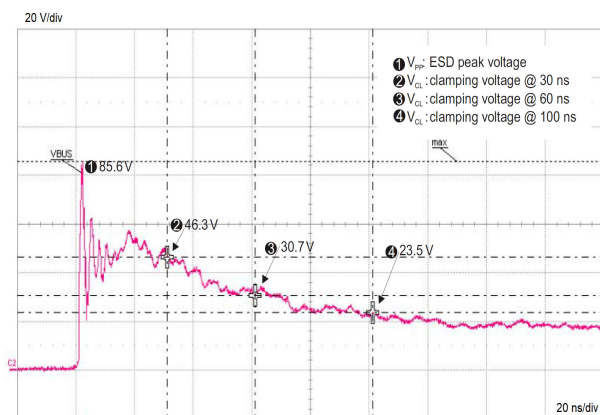
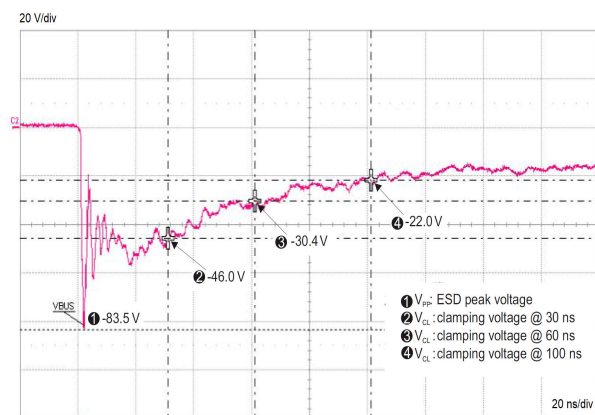
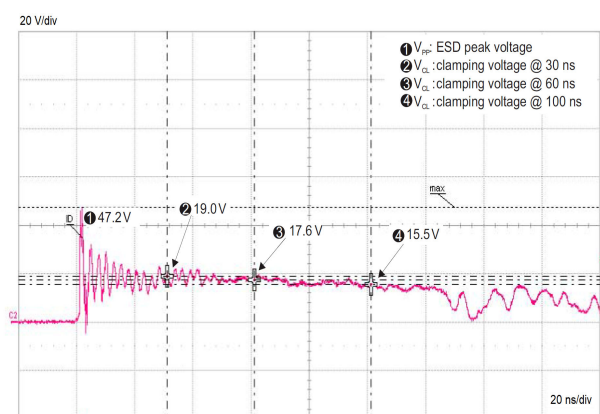
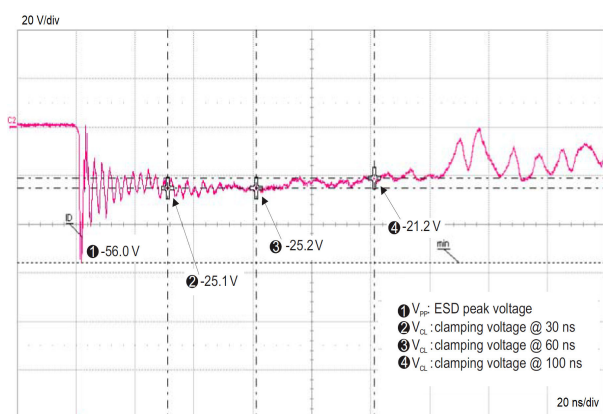
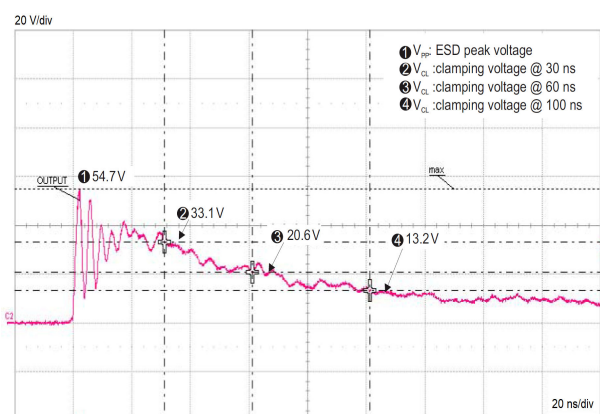
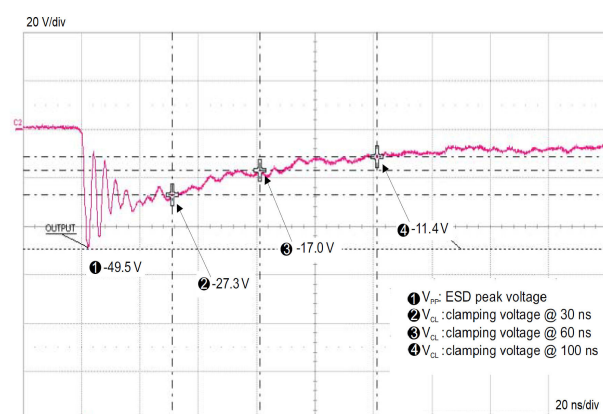
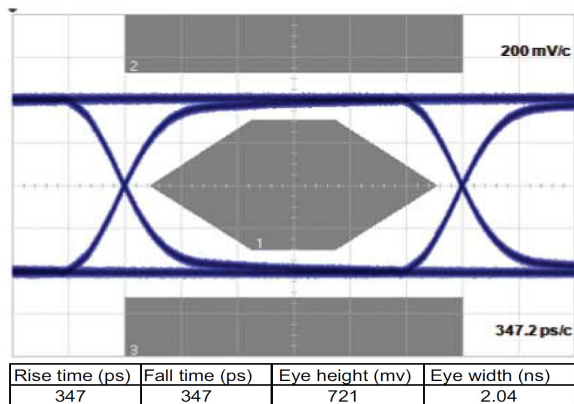
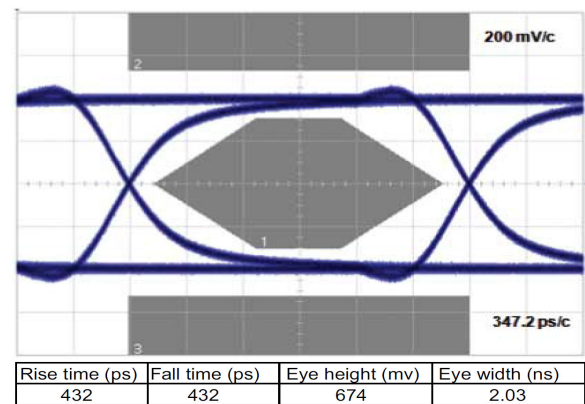
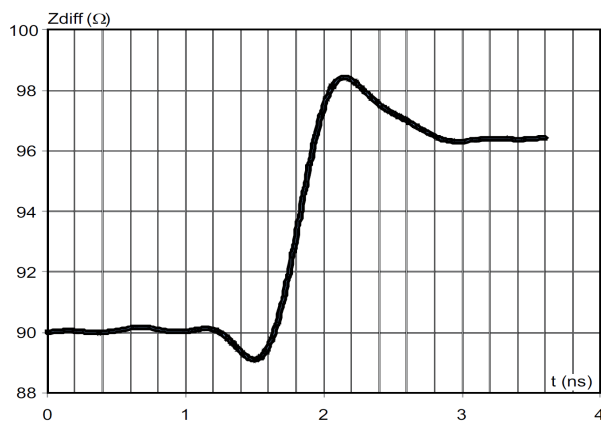
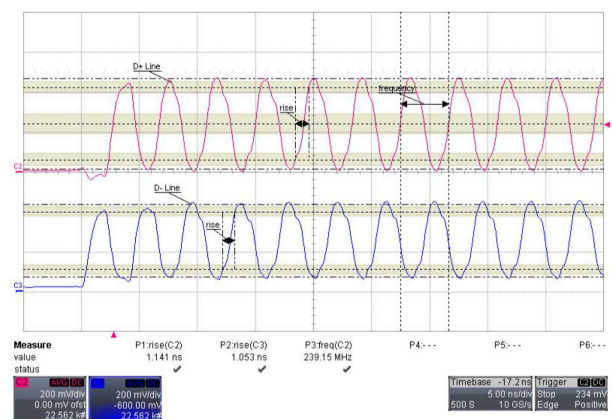
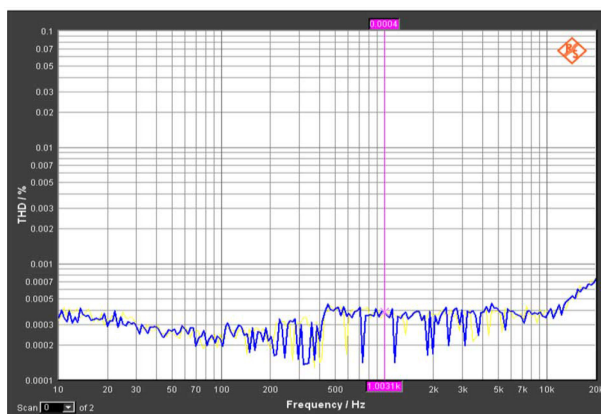
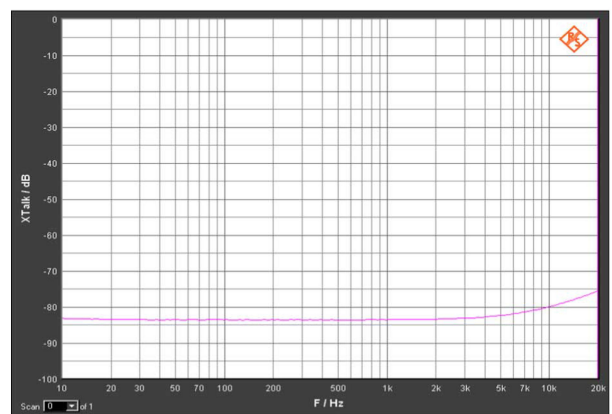
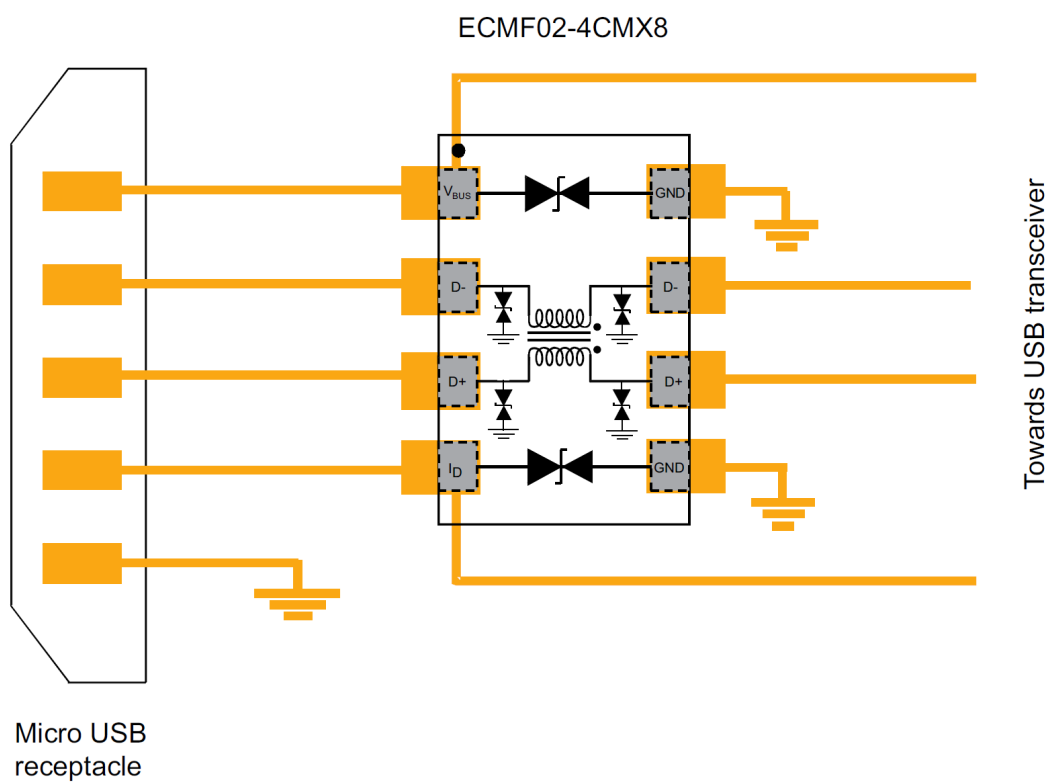
Figure 7. ESD response to IEC 61000-4-2 (+8 kV contact discharge) on V_{BUS}

Figure 8. ESD response to IEC 61000-4-2 (-8 kV contact discharge) on V_{BUS}

Figure 9. ESD response to IEC 61000-4-2 (+8 kV contact discharge) on I_D

Figure 10. ESD response to IEC 61000-4-2 (-8 kV contact discharge) on I_D

Figure 11. ESD response to IEC 61000-4-2 (+8 kV contact discharge) on differential lane

Figure 12. ESD response to IEC 61000-4-2 (-8 kV contact discharge) on differential lane


Figure 13. Eye diagram (loaded by $Z_{diff} = 90 \Omega$) with USB2.0 [mask 1] board only

Figure 14. Eye diagram (loaded by $Z_{diff} = 90 \Omega$) with USB2.0 [mask 1] board with ECM02-4CMX8

Figure 15. TDR measurement (loaded by $Z_{diff} = 90 \Omega$), rise time 400 ps

Figure 16. HS sync

Figure 17. Total harmonic distortion on differential lanes

Figure 18. Crosstalk on differential lane


2 Application schematic

Figure 19. Application schematic



3 Package information

To meet environmental requirements, ST offers these devices in different grades of **ECOPACK** packages, depending on their level of environmental compliance. ECOPACK specifications, grade definitions, and product status are available at: www.st.com. ECOPACK is an ST trademark.

3.1 QFN-8L package information

Figure 20. QFN-8L package outline

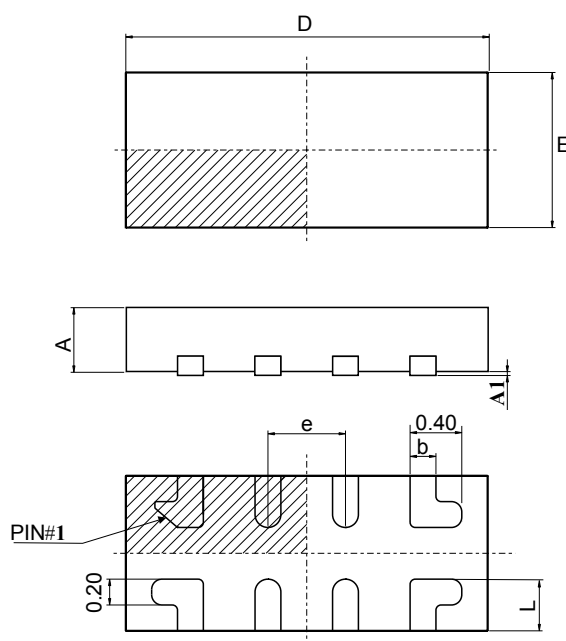


Table 3. QFN-8L mechanical data

| Symbol | Dimesions | | | | | |
|--------|------------|------|------|--------|--------|-------|
| | Milimeters | | | Inches | | |
| | Min. | Typ. | Max. | Min. | Typ. | Max. |
| A | 0.45 | 0.50 | 0.55 | 0.018 | 0.020 | 0.022 |
| A1 | 0.00 | 0.02 | 0.05 | 0.000 | 0.0008 | 0.002 |
| b | 0.15 | 0.20 | 0.25 | 0.006 | 0.008 | 0.10 |
| D | 2.45 | 2.50 | 2.55 | 0.096 | 0.098 | 0.100 |
| E | 1.15 | 1.20 | 1.25 | 0.045 | 0.047 | 0.049 |
| e | 0.45 | 0.50 | 0.55 | 0.018 | 0.020 | 0.022 |
| L | 0.30 | 0.40 | 0.50 | 0.012 | 0.016 | 0.020 |

3.2 Packing information

Figure 21. Footprint

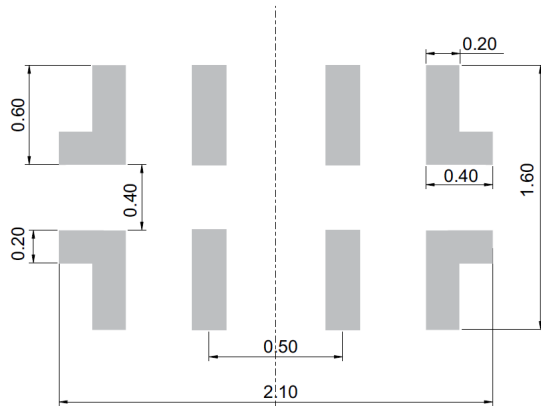


Figure 22. Marking

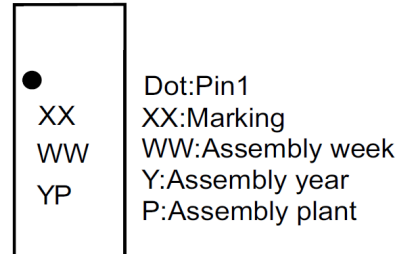
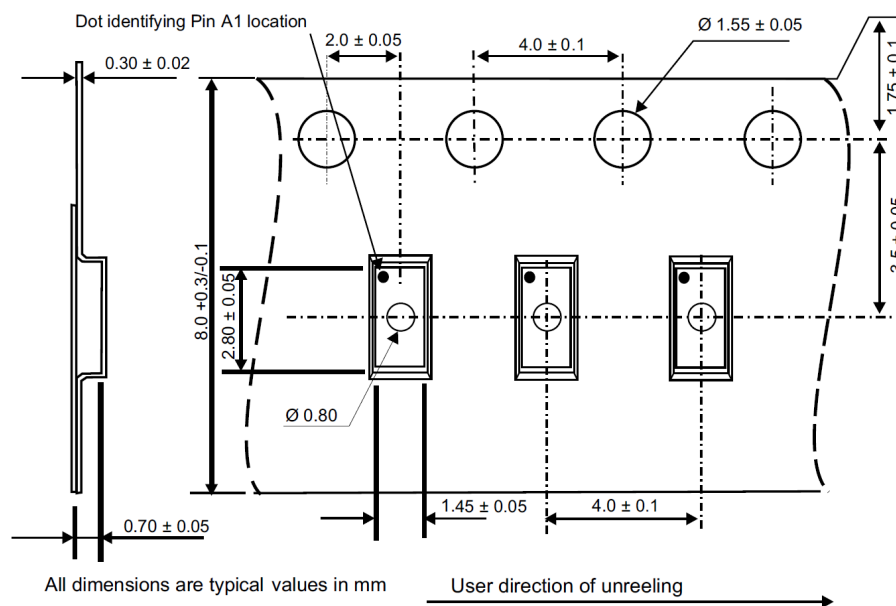


Figure 23. Tape outline



Note: More packing information is available in the AN1751: "EMI Filters: Recommendations and measurements"

4 Ordering information

Figure 24. Ordering information scheme

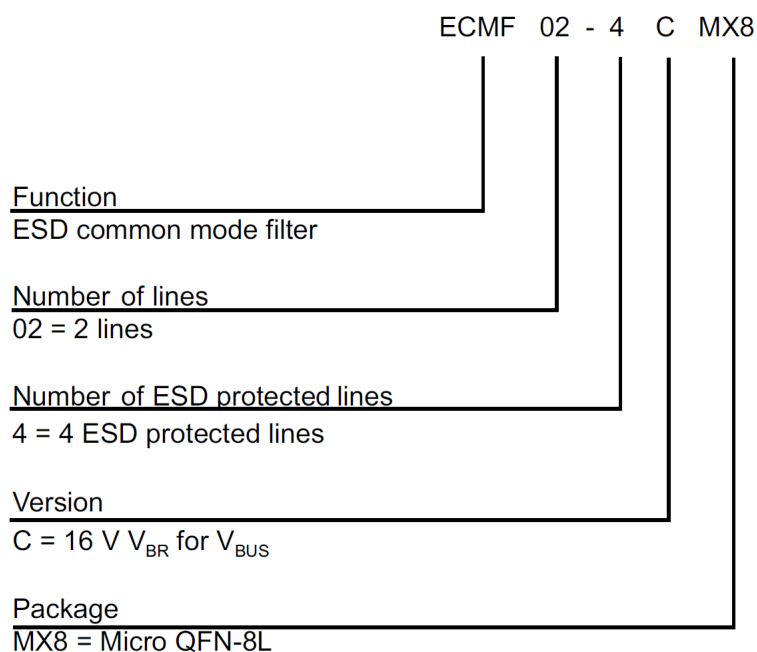


Table 4. Ordering information

| Order code | Marking | Package | Weight | Base qty. | Delivery mode |
|--------------|---------|--------------|--------|-----------|---------------|
| ECMF02-4CMX8 | KG | μ QFN-8L | 3.7 mg | 3000 | Tape and reel |

Revision history

Table 5. Document revision history

| Date | Version | Changes |
|-------------|---------|--|
| 19-Sep-2012 | 1 | Initial release. |
| 27-May-2014 | 2 | Updated <i>Figure 24</i> , <i>Figure 25</i> and reformatted the document. |
| 05-May-2015 | 3 | Added <i>Figure 6</i> . Updated <i>Table 1</i> . Format updated to current standard. |
| 03-Mar-2025 | 4 | Updated Table 1 . Minor text changes. |

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